



PATENT
2390-1-001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : VICTOR HIGGS ET AL.
SERIAL NO.: 09/254,521 EXAMINER: UNKNOWN
FILED : MARCH 8, 1999 ART UNIT: UNKNOWN
FOR : MICRO DEFECTS IN SEMI-CONDUCTORS

#7

CERTIFICATE OF MAILING UNDER 37 CFR 1.8

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to the ASSISTANT COMMISSIONER OF PATENTS, WASHINGTON, DC 20231 on September 29, 1999.

David A. Jackson Reg. No. 26,742
(Name of Registered Representative)

[Signature] 9/29/99
(Signature and Date)

REQUEST FOR CORRECTED FILING RECEIPT

ASSISTANT COMMISSIONER OF PATENTS
WASHINGTON, DC 20231

RECEIVED

NOV 10 1999

Dear Sir:

TECHNOLOGY CENTER 2800

Applicants hereby request that a corrected Formal Filing Receipt (PTO-103X) be issued to correct the title in the above-identified Application.

The title should be changed from "APPARATUS AND METHOD FOR DETECTING MICRO DEFECTS IN SEMI-CONDUCTORS" to

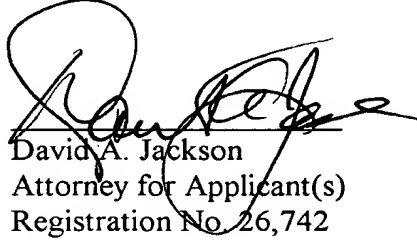
-- MICRO DEFECTS IN SEMI-CONDUCTORS --

as it appears on the Declaration and Power of Attorney filed on March 8, 1999. A copy of said Declaration and Power of Attorney is enclosed.

A copy of the Filing Receipt with the requested correction marked in red is also enclosed.

Applicants accordingly request that the records of the U.S. Patent and Trademark Office be corrected to reflect the correct spelling of the second inventor.

Respectfully submitted,



David A. Jackson
Attorney for Applicant(s)
Registration No. 26,742

KLAUBER & JACKSON
411 Hackensack Avenue
Hackensack, NJ 07601
(201) 487-5800

FILING RECEIPT



2.800
Receipt
UNITED STATES DEPARTMENT OF COMMERCE
Patent and Trademark Office
ASSISTANT SECRETARY AND COMMISSIONER
OF PATENTS AND TRADEMARKS
Washington, D.C. 20231

APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTORNEY DOCKET NO.	DRWGS	TOT CL	IND CL
09/254,521	03/08/99	2877	\$1,100.00	2390-1-001	5	10	2

DAVID A JACKSON
KLAUBER & JACKSON
411 HACKENSACK AVENUE
HACKENSACK NJ 07601

#7
OFR

Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts of Application" ("Missing Parts Notice") in this application, please submit any corrections to this Filing Receipt with your reply to the "Missing Parts Notice." When the PTO processes the reply to the "Missing Parts Notice," the PTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

Applicant(s) VICTOR HIGGS, HERTFORDSHIRE, UNITED KINGDOM;
IAN CHRISTOPHER MAYES, HERTFORDSHIRE, UNITED KINGDOM;
FREDDIE YUN HENG CHIN, HERTFORDSHIRE, UNITED KINGDOM;
MICHAEL SWEENEY, HERTFORDSHIRE, UNITED KINGDOM.

CONTINUING DATA AS CLAIMED BY APPLICANT-

THIS APPLN IS A 371 OF PCT/GB97/02388 09/05/97

FOREIGN APPLICATIONS- GREAT BRITAIN 9618897.4 09/10/96

IF REQUIRED, FOREIGN FILING LICENSE GRANTED 09/17/99

TITLE

~~APPARATUS AND METHOD FOR DETECTING MICRO DEFECTS IN SEMI-CONDUCTORS~~

PRELIMINARY CLASS: 356

RECEIVED

NOV 10 1999

TECHNOLOGY CENTER 2800

DATA ENTRY BY: ORDONEZ, MARTA

TEAM: 11 DATE: 09/17/99

(See reverse for new important information)